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Standard Guide for High-Temperature Static Strain Measurement¹

This standard is issued under the fixed designation E 1319; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This guide covers the selection and application of strain gages for the measurement of static strain up to and including the temperature range from 425 to 650°C (800 to 1200°F). This guide reflects some current state-of-the-art techniques in high temperature strain measurement, and will be expanded and updated as new technology develops.

1.2 This practice assumes that the user is familiar with the use of bonded strain gages and associated signal conditioning and instrumentation as discussed in Refs. (1) and (2).² The strain measuring systems described are those that have proven effective in the temperature range of interest and were available at the time of issue of this practice. It is not the intent of this practice to limit the user to one of the gage types described nor is it the intent to specify the type of system to be used for a specific application. However, in using any strain measuring system including those described, the proposer must be able to demonstrate the capability of the proposed system to meet the selection criteria provided in Section 5 and the needs of the specific application.

1.3 The devices and techniques described in this practice may be applicable at temperatures above and below the range noted, and for making dynamic strain measurements at high temperatures with proper precautions. The gage manufacturer should be consulted for recommendations and details of such applications.

1.4 The references are a part of this practice to the extent specified in the text.

1.5 The values stated in metric (SI) units are to be regarded as the standard. The values given in parentheses are for information purposes only.

1.6 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

¹ This practice is under the jurisdiction of ASTM Committee E28 on Mechanical Testing and is the direct responsibility of Subcommittee E28.01 on Calibration of Mechanical Testing Machines and Apparatus.

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² The boldface numbers in parentheses refer to the list of references at the end of this practice.

2. Referenced Documents

2.1 *ASTM Standards:*

E 6 Terminology Relating to Methods of Mechanical Testing³

3. Terminology

3.1 *Definitions:*

3.1.1 Refer to Terminology E 6 for definitions of terms relating to stress and strain.

3.2 *Definitions of Terms Specific to This Standard:*

3.2.1 Terms pertinent to this guide are described as follows:

3.2.2 *capacitive strain gage*—a strain gage whose response to strain is a change in electrical capacitance which is predictably related to that strain.

3.2.3 *conditioning circuit*—a circuit or instrument subsystem that applies excitation to a strain gage, detects an electrical change in the strain gage, and provides a means for converting this change to an output that is related to strain in the test article. The conditioning circuit may include one or more of the following: bridge completion circuit, signal amplification, zero adjustment, excitation adjustment, calibration, and gain (span) adjustment.

3.2.4 *compensating gage*—a gage element that is subject to the same environment as the active gage element, and which is placed in the adjacent leg of a Wheatstone bridge to provide thermal, pressure, or other compensation in the strain gage system.

3.2.5 *electrical simulation*—a method of calibration whereby a known voltage is generated at the input of an amplifier, equivalent to the voltage produced by a specific amount of strain.

3.2.6 *free filament gage*—a resistive strain gage made from a continuous wire or foil filament which is fixed to the test article along the entire length of the gage, and which is supplied without a permanent matrix.

3.2.7 *gage factor*—the ratio between the unit change of strain gage resistance due to strain and the measurement. The gage factor is dimensionless and is expressed as follows:

$$K = \frac{R - R_0}{R_0} / \frac{L - L_0}{L_0} = \frac{\Delta R}{R_0} / \epsilon \quad (1)$$

³ *Annual Book of ASTM Standards*, Vol 03.01.

where:

- K = gage factor,
- R = strain gage resistance at test strain,
- R_o = strain gage resistance at zero or reference strain,
- L = test structure length under the strain gage at test strain,
- L_o = test structure length under the strain gage at zero or reference strain,
- ΔR = change in strain gage resistance when strain is changed from zero (or reference strain) to test strain, and
- ϵ = mechanical strain $\frac{L - L_o}{L_o}$

3.2.8 *integral lead wire*—a lead wire or portion of a lead wire that is furnished by a gage manufacturer as part of the gage assembly.

3.2.9 *linearity*—the value measured as the maximum deviation between an actual instrument reading and the reading predicted by a straight line drawn between upper and lower calibration points, usually expressed as a percent of the full scale of the sensor range.

3.2.10 *lead wire*—a conductor used to connect a sensor to its instrumentation.

3.2.11 *matrix*—an electrically nonconductive layer of material used to support a strain gage grid. The two main functions of a matrix are to act as an aid for bonding the strain gage to a structure and as an electrically insulating layer in cases where the structure is electrically conductive.

3.2.12 *resistive strain gage*—a strain gage whose response to strain is a change in electrical resistance that is predictably related to that strain.

3.2.13 *shunt calibration*—a method of calibration whereby a resistor or capacitor of known value is placed electrically in parallel with another resistor or capacitor in a circuit, causing a calculable change in the total resistance or capacitance that is predictably related to a specific amount of strain.

3.2.14 *strain, linear*—the unit elongation induced in a specimen either by a stress field (mechanical strain) or by a temperature change (thermal expansion).

3.2.15 *strain gage system*—the sum total of all components used to obtain a strain measurement. May include a strain gage; a means of attaching the strain gage to the test articles; lead wires; splices; lead-wire attachments; signal-conditioning and read-out instrumentation; data-logging system; calibration and control system; environmental protection; or any combination of these and other elements required for the tests.

3.2.16 *static strain*—a strain that is measured relative to a constant reference value, as opposed to dynamic strain, which is the peak-to-peak value of a cyclic phenomenon, without reference to a constant zero or reference value (Fig. 1).

3.2.17 *test article*—an item to which a strain gage system is installed for the purpose of measuring strain in that item.

3.2.18 *thermal compensation*—the process by which the thermal output of a gage system is counteracted through the use of one or more supplementary devices, such as a thermocouple or compensating gage. The counteraction may be integral to the gage system or may be accomplished by data processing methods, or both.

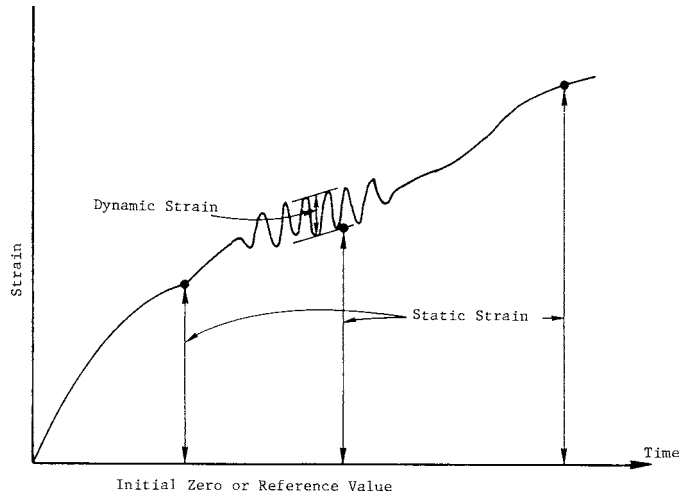


FIG. 1 Relationship Between Static and Dynamic Strain

3.2.19 *thermal output*—the reversible part of the temperature induced indicated strain of a strain gage installed on an unrestrained test specimen when exposed to a change in temperature.

3.2.20 *thermal output-unmounted*—the reversible part of the temperature induced indicated strain of an unmounted strain gage when exposed to a change in temperature.

4. Significance and Use

4.1 The use of this guide is voluntary and is intended for use as a procedures guide for selection and application of specific types of strain gages for high-temperature installations. No attempt is made to restrict the type of strain gage types or concepts to be chosen by the user. The provisions of this guide may be invoked in specifications and procedures by specifying those which shall be considered mandatory for the purpose of the specific application. When so invoked, the user shall include in the work statement a notation that provisions of this guide shown as recommendation shall be considered mandatory for the purposes of the specification or procedure concerned, and shall include a statement of any exceptions to or modifications of the affected provisions of this guide.

5. Gage Selection Criteria

5.1 The factors listed in this section must be considered when selecting a strain gage system for use in the temperature range specified in 1.1. It is recognized that no gage may have all of the desired capabilities to meet all requirements of a particular test. The risk of compromising certain test objectives must be evaluated, and some test objectives may have to be modified to match the capabilities of the available gage selected. Guidelines for this evaluation are provided in Section 9.

5.2 Operating Temperature:

5.2.1 *Isothermal Tests*—Stability of the reference value with respect to time is essential when tests are to be made at constant temperature. The stability of the candidate gage system at the specified temperature must be such that any shift that occurs in the reference value is tolerable for the duration of the test.

5.2.2 Thermal Compensation and Transients—The adequacy of the thermal compensation must be considered when the measurement of strain during a thermal transient is required. Thermal output is a function of temperature, thus its value at a temperature depends not only on temperature, but on the temperature history followed in reaching that temperature. If significant hysteresis in the thermal response is present, large errors or uncertainties can result. This is especially true when the calibration procedure used to characterize the thermal output does not accurately reflect the temperature sequence to which the gages will be exposed during testing. If the response time of the compensation is exceeded, the resulting uncertainty must be considered. The ability of the gage system to withstand the transient without a detrimental shift of the reference value must be verified. This is true whether or not strain is measured during the transient. Any gage factor change as a function of temperature change must also be considered.

5.2.3 *Precalibration:*

5.2.3.1 Thermal output calibration on the structure is usually not possible and precalibration of gages on a similar material is necessary. However, variations of up to 0.5 ppm/°F are possible within a material. Often, rolling direction will influence thermal expansion coefficient.

5.2.3.2 Precalibration of resistive or capacitive strain gages is performed using a calibration fixture made from material similar to the test article. The calibration fixture must be made to precisely fit the gage, especially if curvature is involved. Experience has shown mating parts must be lapped together to provide uniform clamping pressure around the periphery of the gage weld area.

5.2.3.3 The calibration test should be repeated to ensure precise duplication of the calibration. Zero return should also repeat exactly. If calibration data does not repeat; either the calibration set-up or the gages are faulty.

5.2.4 *Post Test Calibration:*

5.2.4.1 A more precise thermal output calibration can be achieved after the test by removing the test gage (cut it out of the structure) and running a precision test on the test gage still attached to the test article material. The test coupon is relieved of all induced stresses (thermal, mechanical, residual) and is free to expand freely with temperature. The integral gage lead wire should be exposed to thermal gradients similar to those that occurred during the test program.

5.3 Duration of Test—The ability of all parts of the gage system to function for the specified duration of test should be demonstrated; if multiple tests are required on the same test article, the capability and effect of gage replacement must also be established.

5.4 Strain Rate—The time response of the candidate gage system must be adequate to meet test requirements if rapid changes of load are anticipated. It may be necessary to design the loading rate of the test to accommodate limitations of the strain measurement system selected.

5.5 Environment—Some gages are limited to specific operating environments and therefore, the gage system selected must be capable of withstanding the environment in which it will operate. Such limitations must be carefully considered when selecting the gage system to be used. Factors such as

pressure, vibration, radiation, magnetic fields, humidity, etc., must be considered. The ambient and test environments of the elements of the strain gage system must be considered in the selection of lead wires, connectors, instrumentation, and seals (when required).

5.6 *Strain Range:*

5.6.1 Total Strain Range—The maximum strain ranges of the candidate gage types must be defined and must be adequate for the test. Mechanical strain attenuators, when permissible, may be added to extend the strain range of a given strain gage system, subject to the limitation of **5.6.2**.

5.6.2 Resolution—The ability of the candidate gage to measure small increments of strain within the total strain range should be compared with the incremental strain measurement requirements of the test. When mechanical strain attenuators are used, the resulting loss of resolution must be considered.

5.7 Strain Gradient—The gage length of the candidate gage establishes the length over which the unit strain is averaged. This factor must be considered.

5.8 Uncertainty Factor—Uncertainty information that is available from the manufacturer must be considered, in conjunction with conditions which are unique to the test, in order to estimate the total uncertainty.

5.9 Space Requirements—If space on or adjacent to the test article is limited, the space requirements for the complete strain gage system may be a critical consideration in determining the suitability of a particular gage system. Working space for installation of the system may also be limited and must also be considered. Space adjacent to the installed strain gage should be provided for installation of room-temperature strain gages required for making in-place calibrations.

5.10 Effects of the Strain Gage on the Test Article—In most cases the reinforcing effect of the strain gage on the test article is negligible, particularly in the case of capacitance gages where the spring rate is extremely low. If a weldable gage is to be used on thin sections, an evaluation of the reinforcing effect should be made. Technical data concerning this effect can be obtained from a strain gage manufacturer.

6. Characteristics of Available Gages

6.1 The two basic types of strain gages used for high temperature static strain measurements are resistive strain gages and capacitive strain gages.

6.1.1 Resistive gages are usually small, low profile units superbly suited for dynamic strain measurements and relatively short-term static measurements. Because high temperatures cause metallurgical instability, oxidation, relaxation, and phase change of the strain sensing materials, all of which affect resistance change, resistive gages are generally not used for long-term measurements.

6.1.2 Capacitive strain gages are devices that measure changes in geometry and are unaffected by temperature or temperature changes, oxidation, relaxation, creep, grain growth, or phase change. They are best suited for measuring creep strains, or for very long-term tests on applications where a relatively large gage can be used, and when the gage will not be subjected to high vibration, gravity, or acceleration forces, shock loading, or an electrically conductive atmosphere.

6.1.3 When selecting a specific strain gage for a given application, the strain gage system must be qualified for the specific conditions under which it will be required to operate and for the characteristics it must exhibit under service conditions. This section describes some of the capability of currently available strain gages, suitable for use in the specified temperature range, to meet the selection criteria of Section 5.

6.1.4 Wire and foil free-filament strain gages may be usable to approximately 400°C (750°F) under static conditions, and to approximately 1250°C (2280°F) for certain dynamic applications. However, the bonding methods used (ceramic cement, flame spray) are cumbersome and difficult to employ on large structures, particularly under field conditions. Ceramic cements require heat-curing and are generally unsuitable for large structures such as nuclear or fossil-fuel power-generating equipment. Flame spray is also difficult to use in the field. Free-filament gages, although useful for strain measurement on small items under laboratory conditions, are, therefore, not included in this practice. This does not preclude the use of these strain gages for specific tests based on the selection criteria of Section 5.

6.1.5 The gages described in this section have been used at high temperature for sufficient time and with sufficient success to warrant consideration in this guide. Each type has unique features, advantages, and limitations which must be carefully evaluated relative to the selection factors of Section 5.

6.2 Bonded Weldable Resistance Strain:

6.2.1 This gage, shown in Fig. 2, consists of a free filament strain gage ceramic bonded to a shim. While it is not usually sealed or intended for underwater use, some hermetically sealed gages are bonded to the shim with ceramic cements or flame sprayed ceramics. The following alloys are available: (1) self temperature compensated nickel chrome alloy sensors useable to 340°C in quarter bridge (single element) configuration, (2) platinum tungsten and palladium chrome alloy sensors (dual element) compensated with platinum elements in half bridge configuration, and (3) iron chrome aluminum alloys having low temperature coefficient are available in half or full bridge configuration for applications where active-dummy combinations (slow temperature changes) are useable.

6.2.2 Except for long-term stability, the bonded strain gage has excellent performance with minimal hysteresis, small zero shift, long fatigue life, and accurate gage factor among its salient features. An integral weldable terminal and integral high temperature cable are usually supplied with these units, especially when the gages are supplied precalibrated for apparent strain.

6.2.3 The thermal output of the dual element gages can be adjusted to produce a zero output at any two selected temperatures. The thermal output of the platinum tungsten gage is usually well within ±200 µm/m between 20 and 500°C. The

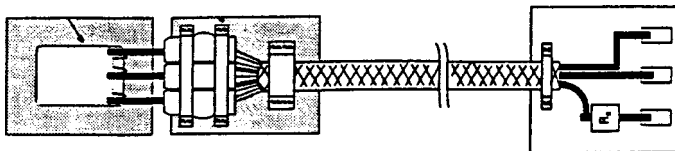


FIG. 2 Bonded Weldable Resistance Strain Gage

shape of the thermal output curve is influenced by the thermal expansion characteristics of the test material. Fig. 3 shows the completion circuit for the dual element half bridge gage. There are two methods of compensation, (1) NASA method (20) and (2) the wire method (21).

6.2.4 With the NASA method, the gage is manufactured to fit a specific type of material with the platinum thermometer element resistance value selected to provide an almost perfectly balanced bridge. This permits a three wire cable to be used without sacrificing inherent lead wire compensation. The five wire system employs a thermometer element sufficiently high in resistance to compensate on virtually any material. This makes for universal compensation on any material. The drawback of this universal system is that five wires are required. A shunt resistor R_g placed across the thermometer element only shunts the output of the compensator. If the shunt resistor were placed across the thermometer and lead wire, inherent lead compensation would be sacrificed.

6.2.5 The user may precalibrate the gage and cable system and determine the bridge completion resistor values using a set of equations provided with the gage, or the gage may be precalibrated at the factory (22) and supplied precalibrated with the bridge completion resistors included in a network attached to the cool end of the cable. The user needs only to hook up the gage as a full bridge transducer and insert the calibration curve into his data acquisition system.

6.3 Hermetic Weldable Resistance Strain Gage—This gage, which is shown several times the actual size in Fig. 4, is hermetically sealed and furnished with integral lead wires, and may be used in a variety of severe environments at high temperature. The strain tube is welded to a thin mounting flange, which is welded to the surface of the test article, thus providing transfer of strain from the test article to the gage. Although Fig. 4 shows stainless steel strain tube, mounting flange, and cladding of the integral lead wire, other materials are available to meet the requirements of specific applications; consult the manufacturer for available materials. Within limits, the thermal output of the gage due to temperature can be adjusted to produce a zero output at any two selected temperatures by inserting a temperature compensation resistor, R_{tc} in Fig. 5 in series with either the active or compensating gage element; the proper resistor is furnished by the manufacturer. Because of the added resistance in series with one of the gage elements, the bridge-completion resistors must also be adjusted for balance by adding a balancing resistor (R_{bal} in Fig. 5) in the opposite half of the bridge. This resistor is also furnished by the gage manufacturer. The value of R_{bal} is based on the use of 120

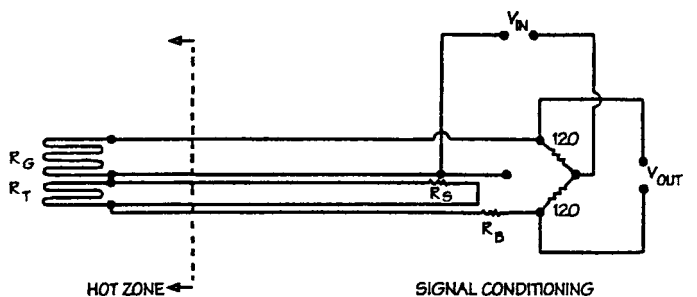


FIG. 3 Five Wire Circuit

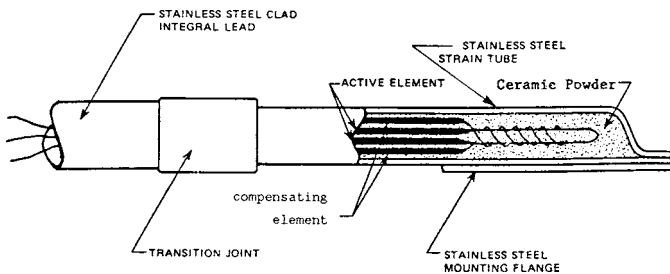


FIG. 4 Hermetic Weldable Resistance Strain Gage

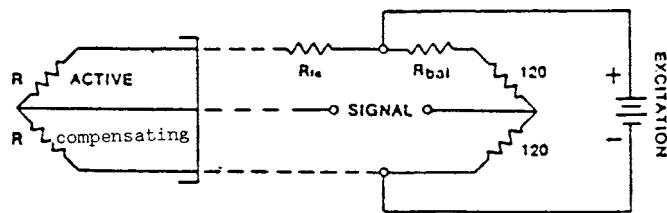


FIG. 5 Bridge Completion Network and Power Supply

Ω bridge-completion resistors to produce a balanced bridge when the gage is connected.

6.3.1 Operating Temperature and Thermal Stability:

6.3.1.1 The platinum tungsten element is essentially stable for short-term testing to 500°C (days) with shorter excursions up to 580°C (hours) without damage to the gage. Longer tests (weeks) can be run to up to 425°C. Beyond these limits is the domain of the capacitive strain gage.

6.3.2 Thermal Compensation and Transients—Thermal output characteristics must be considered for operation at varying temperatures. This information is furnished by the manufacturer for use of the gage on the material specified by the user. For precise evaluation, a calibration is necessary, with thermal output determined at the temperatures of interest. Temperatures should be measured by a thermocouple(s) mounted immediately adjacent to the gage. Thermal output and hysteresis of a test are usually repeatable under identical test conditions; however, even the slightest change in test conditions may result in a change of thermal output, hysteresis, or both. To qualify the gage for thermal shock, laboratory tests should be made to determine the stability characteristics and the limits of thermal compensation.

6.3.3 Electrical Requirements—Bridge completion, as shown in Fig. 5, is required. While there are several standard strain measuring systems with bridge completion capability available, it is recommended that, for static strain measurement in the temperature range of this practice, an individual signal conditioning circuit having the following features be provided for each gage.

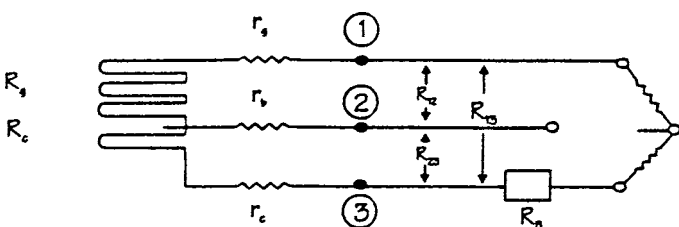
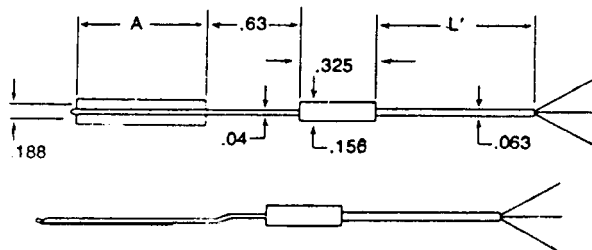


FIG. 6 Three Wire Circuit

TYPE	SG 425	MG 425
DIM. A	1.09	.62



NOTE 1—All dimensions are in inches.

FIG. 7 Dimensions of Hermetic Weldable Resistance Strain Gage

6.3.4 Excitation Power Supply—A power supply for providing constant DC voltage, continuously variable from 1 V to 15 V across a 120 Ω external load, is required. Constant current excitation cannot be used with some of the compensation techniques generally used with this gage. If more than one bridge circuit is excited by the same power supply, the electrical configuration must provide electrical isolation of each circuit to protect it in the event of a direct short of the excitation of any of the adjacent circuits.

6.3.5 Balance Control—Means shall be provided for balancing the bridge with a T balance resistor network across the completion half of the bridge. This is not required in the event that the data acquisition equipment automatically compensates for initial bridge unbalance.

6.3.6 Shunt Calibration—Shunt calibration capability should be provided on the completion half of the bridge. Shunting of the active or compensating legs of the bridge is not recommended because of changes in the resistances of the lead wires with temperature. Multiple shunt calibration is recommended.

6.3.7 Circuit—The signal conditioner must be capable of handling a half bridge circuit with precision completion resistors, configured to permit the addition of series balance resistors to either leg. It is recommended that the signal conditioner be able to accommodate a half bridge, five wire hookup, with two additional leads, for remote sensing of the excitation voltage.

6.3.8 Means must be provided for continuous monitoring of bridge excitations and bridge output. An amplifier may or may not be required, depending on the input capability of the measuring system used. Amplifier requirements are not covered in this guide; however, a good quality, stable amplifier with true differential input, and input impedance of not less than 10 M Ω and shunted by 750 pF when DC-coupled, is recommended.

6.4 Differential Capacitance Strain Gage—Fig. 8 identifies major elements of the gage and shows principal dimensions. Fig. 9 shows an isometric view. The compensating rod (1) is usually made of the same material as the test article (specified by user). The cylindrical excitation plates (2) are mounted coaxially on, but are electrically insulated from the compensating rod. The sensing ring (3) is mounted coaxially with the excitation plates but is separated from them by an air gap. The attachment ribbons (4), (see the isometric view in Fig. 9)

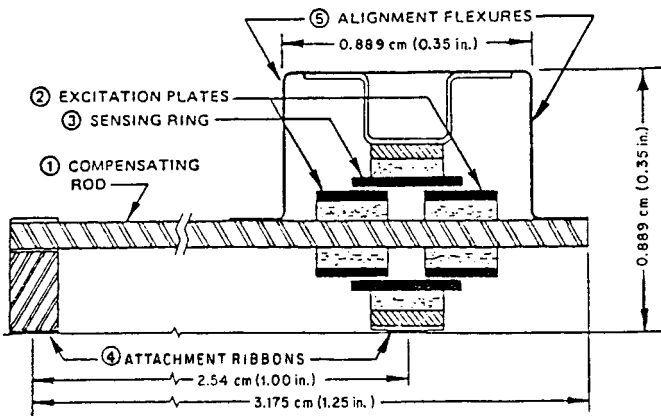


FIG. 8 Differential Capacitance Strain Gage

provide means for welding the gage to the test article. The alignment flexures (5) (see the isometric view in Fig. 9), maintain the coaxial alignment of the sensing ring relative to the excitation plates and compensating rod. Leads from the three capacitor plates are brought to a terminal (6) which is also attached to the test article by spot welding. The complete strain measuring system consists of a half bridge differential capacitance strain gage, a capacitive signal conditioner, and the interconnecting leads.

6.4.1 With this type of gage, strain in the test article causes linear movement of the excitation plates relative to the colinear sensing ring. Changes in capacitance result when more or less area of the sensing ring overlaps the respective excitation plates; the linear gap between the excitation plates and the annular gap between the excitation rings and the sensing rings remain constant. Temperature compensation is achieved by use of a compensating rod made from a material having thermal expansion characteristics similar to those of the test article. Both the gage and the test article are instrumented with thermocouples to obtain data for computing the corrections required if there is a temperature difference between the compensating rod and the surface of the test article. These thermocouples (9) are shown in Fig. 9 and are connected to the thermocouple terminals (8), which are spot welded to the test article. Factors affecting gage selection are discussed in the following paragraphs.

6.4.2 *Operating Temperature and Thermal Stability*—The gage operates effectively over the entire 425°C to 650°C (800°F to 1200°F) range covered by this guide. Average drift rates for long term tests (2000 to 12 000 h) are typically from 0.01 to 0.05 $\mu\text{m}/\text{m}/\text{h}$ at approximately 640°C (1180°F). Short term drift rates can be up to 1 $\mu\text{m}/\text{m}/\text{h}$ during the first 100 h of operation.

6.4.3 *Thermal Compensation and Transients*—The gage has been used successfully at thermal transients of up to 17°C/seconds (30°F/seconds). For varying temperature conditions, thermal output should be generated in situ utilizing an integral surface thermocouple. Thermal output and hysteresis of a test are usually, within limits repeatable under identical test conditions. Even the slightest change in test conditions, however, may result in a change of apparent strain, hysteresis, or both.

6.4.4 *Life Expectancy*—Successful tests of more than 12 000 h duration have been reported. Cyclic fatigue data are not available (6).

6.4.5 *Strain Rate*—The gage is rated for less than 2 % nonlinearity to 30 000 $\mu\text{e}/\text{s}$ at 21°C (70°F) (4).

6.4.6 *Environmental Factors Other Than Temperature*—The gage has usually been used in air at atmospheric pressure, but has performed satisfactorily in helium, hydrogen, nitrogen, and an air-argon mixture of unknown composition. The experimenter should consult the manufacturer before attempting to use the system in gases other than those noted.

6.4.6.1 *Nuclear Radiation Resistance*—The gage contains no organic or other materials that will deteriorate under nuclear radiation.

6.4.6.2 *Magnetic Properties*—See Ref. (4).

6.4.7 *Strain Range*—The total rated strain range is 40 000 μe for the 25.4 mm gage length Model, and 160 000 $\mu\text{m}/\text{m}$ for the 6.35 mm Model.

6.4.8 *Gage Length*—Strain is averaged over the active gage lengths of 25.4 mm (1 in.) and 6.35 mm (0.25 in.), respectively.

6.4.9 *Space Requirements*—Major dimensions of the gage are shown in Fig. 8 and Fig. 9. The user must install a sheet metal housing (furnished by the user) over the installed gage system.

6.4.10 *Electrical Requirements*—The electronics required for conversion of the gage differential capacitance output to an analog voltage was developed specifically for use with this gage. The system provides both an excitation to, and a calibrated output from the strain gage. Each module provides dual excitation signals at a carrier chosen to eliminate interference from line-frequency harmonics. The return signal from the gage is amplified at a calibrated set point and then is converted to a DC signal that is directly proportional to the displacement applied to the gage (that is, the strain). The use of a charge amplifier input eliminates the effect of signal lead wire-to-shield capacitance, minimizing sensitivity of the gage to lead wire length. This system has a full scale output of 5 V. The minimum strain in the gage to produce the full scale output of 5 V is 2500 $\mu\text{m}/\text{m}$.

6.5 *Variable Capacitance Strain Gage*—Fig. 10 shows a cross section and major dimensions of this gage. It is a single capacitor, variable capacitance device that works on the principle that changes in gage length (the distance between the welds in Fig. 10) are mechanically amplified to produce a magnified movement of the electrodes relative to one another, normal to the plane of the electrodes, which causes a change in the air gap between the electrodes and thus the capacitance. The electrode plates are mounted on arches of different radii. Capacitance of this type of gage is typically between 0.4 and 1.5 pF over a working range of 10 000 $\mu\text{m}/\text{m}$.

6.5.1 The capacitive output of this gage is nonlinear with strain as shown in Fig. 11, which illustrates the typical relationship obtained by calibrating the gage at room temperature. The gage is attached to the surface of the test article by single spot welds at each end (Fig. 10), and is made from a highly stable alloy with temperature coefficient matching closely either that of the stainless steels or ferritic steels used at elevated temperatures. However, there may be some thermal